

Notice of References Cited	Application/Control No. 10/042,080	Applicant(s)/Patent Under Reexamination BERRY ET AL.	
	Examiner John P Trimmings	Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,642,362	06-1997	Savir, Jacob	714/726
	B	US-6,195,776	02-2001	Ruiz et al.	714/738
	C	US-5,150,366	09-1992	Bardell et al.	714/728
	D	US-5,278,842	01-1994	Berry et al.	714/726
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Scan Latch Design for Delay Test", Jacob Savir, 1997 Test Conference (IEEE Proceedings International), Nov 1-6 1997, pp 446-453.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.